

## 54F/74F00 Quad 2-Input NAND Gate

### **General Description**

### **Features**

This device contains four independent gates, each of which performs the logic NAND function.

■ Guaranteed 4000V minimum ESD protection

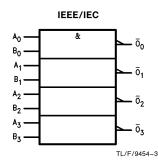
Commercial	Military	Package Number	Package Description
74F00PC		N14A	14-Lead (0.300" Wide) Molded Dual-In-Line
	54F00DM (Note 2)	J14A	14-Lead Ceramic Dual-In-Line
74F00SC (Note 1)		M14A	14-Lead (0.150" Wide) Molded Small Outline, JEDEC
74F00SJ (Note 1)		M14D	14-Lead (0.300" Wide) Molded Small Outline, EIAJ
	54F00FM (Note 2)	W14B	14-Lead Cerpack
	54F00LM (Note 2)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C

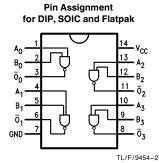
Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

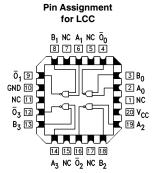
Note 2: Military grade device with environmental and burn-in processing. Use suffix = DMQB, FMQB and LMQB.

### **Logic Symbol**

### **Connection Diagrams**







TL/F/9454-1

### **Unit Loading/Fan Out**

		54F/74F			
Pin Names	Description	U.L. HIGH/LOW	Input I <sub>IH</sub> /I <sub>IL</sub> Output I <sub>OH</sub> /I <sub>OL</sub>		
$\frac{A_n, B_n}{\overline{O}_n}$	Inputs Outputs	1.0/1.0 50/33.3	20 μA/-0.6 mA -1 mA/20 mA		

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### **Absolute Maximum Ratings** (Note 1)

 $\begin{array}{lll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to} + 125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to} + 175^{\circ}\mbox{C} \\ \mbox{Plastic} & -55^{\circ}\mbox{C to} + 150^{\circ}\mbox{C} \\ \end{array}$ 

 $V_{\mbox{\footnotesize CC}}$  Pin Potential to

Ground Pin -0.5V to +7.0V

 $\begin{array}{ll} \mbox{Input Voltage (Note 2)} & -0.5\mbox{V to } +7.0\mbox{V} \\ \mbox{Input Current (Note 2)} & -30\mbox{ mA to } +5.0\mbox{ mA} \end{array}$ 

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

 $\begin{array}{lll} & -0.5 \text{V to V}_{\text{CC}} \\ & \text{TRI-STATE} \text{® Output} \end{array} \\ & -0.5 \text{V to } +5.5 \text{V} \\ \end{array}$ 

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) ESD Last Passing Voltage (Min) 4000V Note 1: Absolute maximum ratings are values beyond which the device may

be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

# Recommended Operating Conditions

Free Air Ambient Temperature

Commercial  $0^{\circ}\text{C to } + 70^{\circ}\text{C}$ 

Supply Voltage

Commercial +4.5V to +5.5V

### **DC Electrical Characteristics**

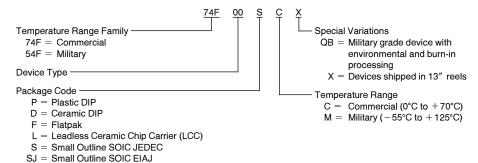
Symbol	Parameter .		54F/74F			Units	Vcc	Conditions	
			Min	Тур	Max	Omis	•00	Conditions	
$V_{IH}$	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
$V_{CD}$	Input Clamp Diode Voltage				-1.2	V	Min	$I_{\text{IN}} = -18 \text{ mA}$	
V <sub>OH</sub>	Output HIGH Voltage	54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub> 74F 5% V <sub>CC</sub>	2.5 2.5 2.7			V	Min	$I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$ $I_{OH} = -1 \text{ mA}$	
V <sub>OL</sub>	Output LOW Voltage	54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub>			0.5 0.5	٧	Min	$I_{OL} = 20 \text{ mA}$ $I_{OL} = 20 \text{ mA}$	
liH	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	$V_{\text{IN}} = 2.7V$	
I <sub>BVI</sub>	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	V <sub>IN</sub> = 7.0V	
I <sub>CEX</sub>	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$	
V <sub>ID</sub>	Input Leakage Test	74F	4.75			٧	0.0	$I_{\text{ID}} = 1.9 \ \mu\text{A}$ All other pins grounded	
I <sub>OD</sub>	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V <sub>IOD</sub> = 150 mV All other pins grounded	
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	V <sub>IN</sub> = 0.5V	
los	Output Short-Circuit Current		-60		-150	mA	Max	$V_{OUT} = 0V$	
Icch	Power Supply Current			1.9	2.8	mA	Max	V <sub>O</sub> = HIGH	
I <sub>CCL</sub>	Power Supply Current			6.8	10.2	mA	Max	$V_O = LOW$	

### **AC Electrical Characteristics**

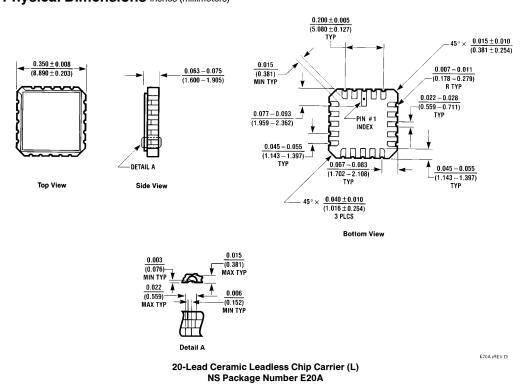
	Parameter	74F			54F		74F		Units
Symbol		$\begin{aligned} \textbf{T}_{\textbf{A}} &= +25^{\circ}\textbf{C} \\ \textbf{V}_{\textbf{CC}} &= +5.0\textbf{V} \\ \textbf{C}_{\textbf{L}} &= 50~\textbf{pF} \end{aligned}$			$ extsf{T}_{ extsf{A}},  extsf{V}_{ extsf{CC}} =  extsf{Mil} \  extsf{C}_{ extsf{L}} =  extsf{50 pF}$		T <sub>A</sub> , V <sub>CC</sub> = Com C <sub>L</sub> = 50 pF		
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	2.4	3.7	5.0	2.0	7.0	2.4	6.0	
t <sub>PHL</sub>	$A_n$ , $B_n$ to $\overline{O}_n$	1.5	3.2	4.3	1.5	6.5	1.5	5.3	ns

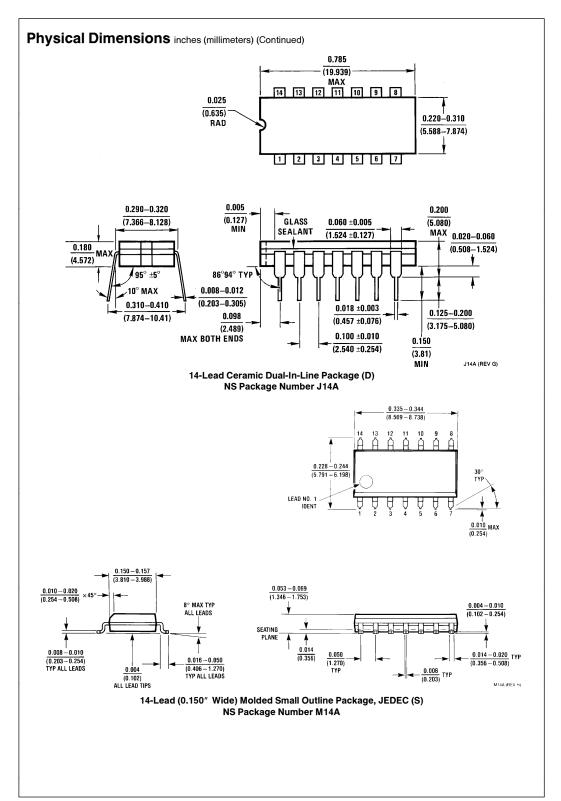
### **Ordering Information**

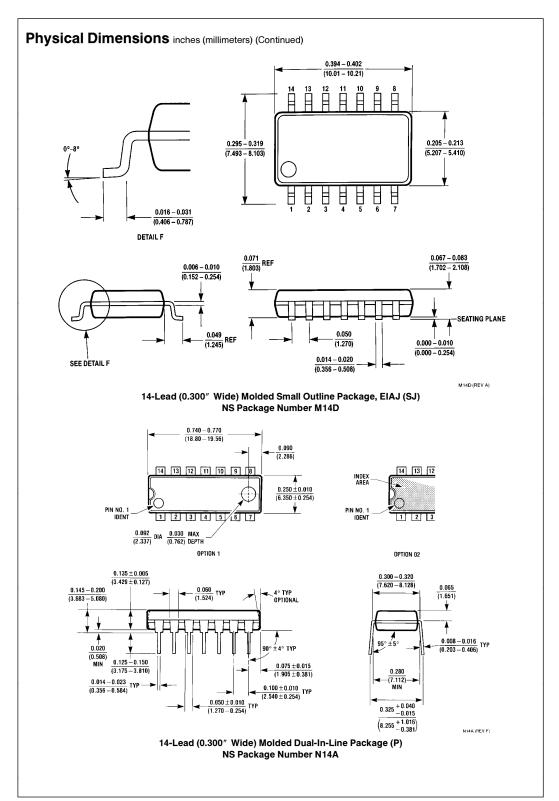
The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



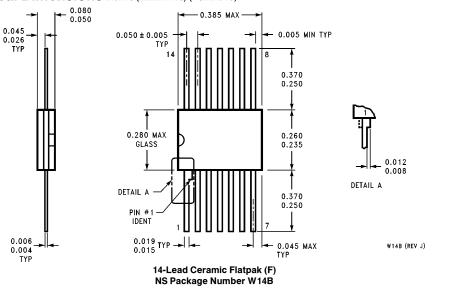
### Physical Dimensions inches (millimeters)







### Physical Dimensions inches (millimeters) (Continued)



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